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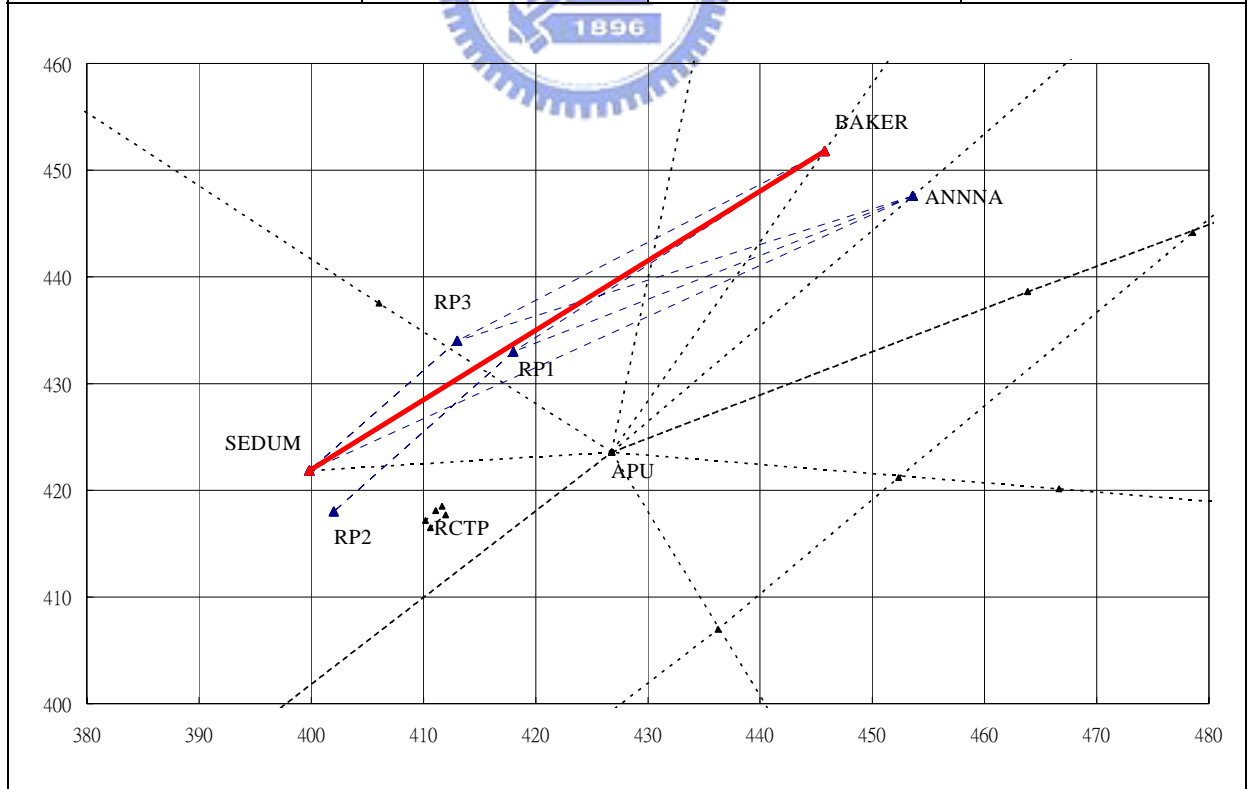
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附錄一、各路線、速度及高度指示一覽表

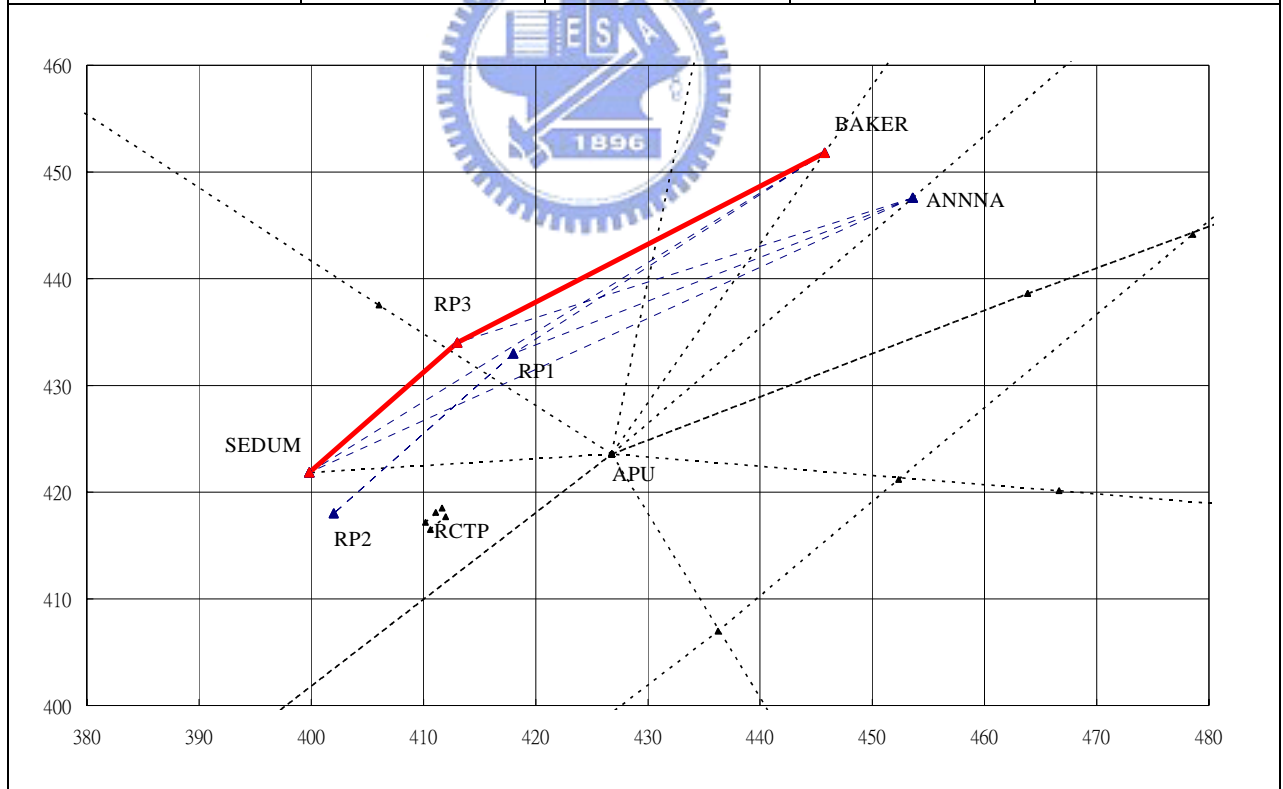
附表 1 R1-速度程序及高度指示一覽表

速度程序 (Speed Profile)	BAKER	SEDUM 前 20 哩	SEDUM
Profile A (Normal) 通過時間: 602s (±5%)	GS: 390kt (IAS: 290kt) FL200	GS: 290kt (IAS: 240kt) 10000ft	GS: 250kt (IAS: 230kt) 5000±1000ft
Profile B (Low Speed) 通過時間: 655s (±5%)	GS: 340kt (IAS: 240kt) FL200	GS: 290kt (IAS: 240kt) 10000ft	GS: 250kt (IAS: 230kt) 5000±1000ft
Profile C (High Speed) 通過時間: 534s (±5%)	GS: 410kt (IAS: 310kt) FL200	GS: 360kt (IAS: 310kt) 10000ft	GS: 280kt (IAS: 255kt) 5000±1000ft



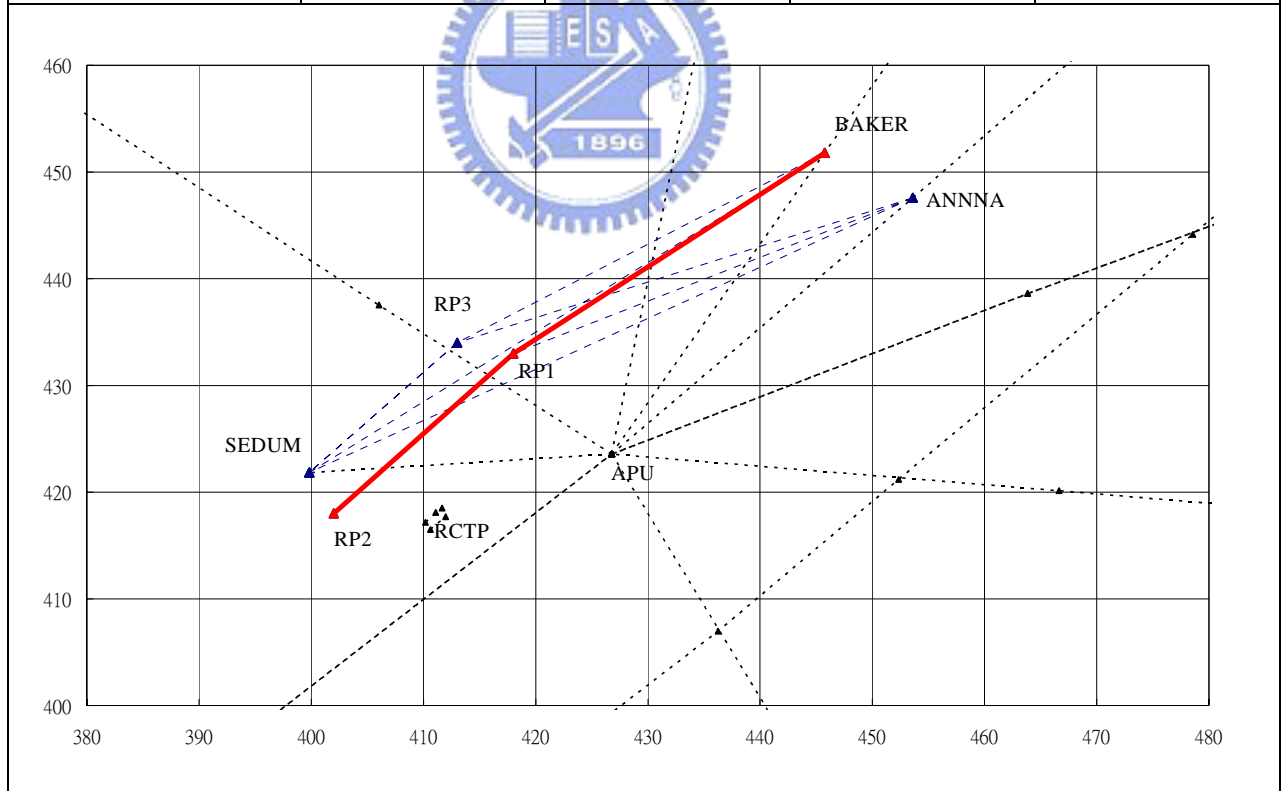
附表 2 R2-速度程序及高度指示一覽表

速度程序 (Speed Profile)	BAKER	RP3 前 6 哩	RP3	SEDUM
Profile A (Normal) 通過時間: 612s (±5%)	GS: 390kt (IAS: 290kt) FL200	GS: 350kt (IAS: 295kt) FL110	GS: 290kt (IAS: 240kt) 10000ft	GS: 250kt (IAS: 230kt) 5000±1000ft
Profile B (Low Speed) 通過時間: 666s (±5%)	GS: 340kt (IAS: 240kt) FL200	無	GS: 290kt (IAS: 240kt) 10000ft	GS: 250kt (IAS: 230kt) 5000±1000ft
Profile C (High Speed) 通過時間: 543s (±5%)	GS: 410kt (IAS: 310kt) FL200	無	GS: 360kt (IAS: 310kt) 10000ft	GS: 280kt (IAS: 255kt) 5000±1000ft



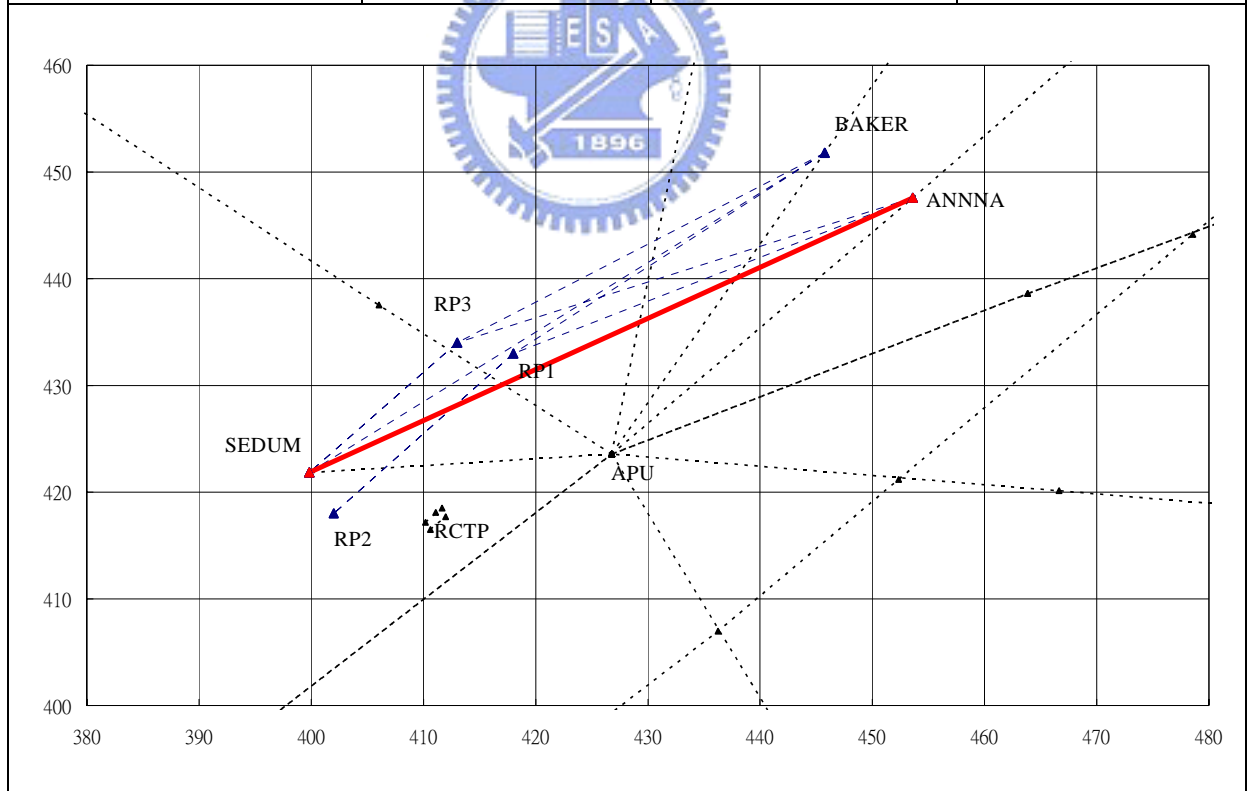
附表 3 R3-速度程序及高度指示一覽表

速度程序 (Speed Profile)	BAKER	RP1 前 6 哩	RP1	RP2
Profile A (Normal) 通過時間: 602s (±5%)	GS: 390kt (IAS: 290kt) FL200	GS: 350kt (IAS: 295kt) FL110	GS: 290kt (IAS: 240kt) 10000ft	GS: 250kt (IAS: 230kt) 5000±1000ft
Profile B (Low Speed) 通過時間: 655s (±5%)	GS: 340kt (IAS: 240kt) FL200	無	GS: 290kt (IAS: 240kt) 10000ft	GS: 250kt (IAS: 230kt) 5000±1000ft
Profile C (High Speed) 通過時間: 534s (±5%)	GS: 410kt (IAS: 310kt) FL200	無	GS: 360kt (IAS: 310kt) 10000ft	GS: 280kt (IAS: 255kt) 5000±1000ft



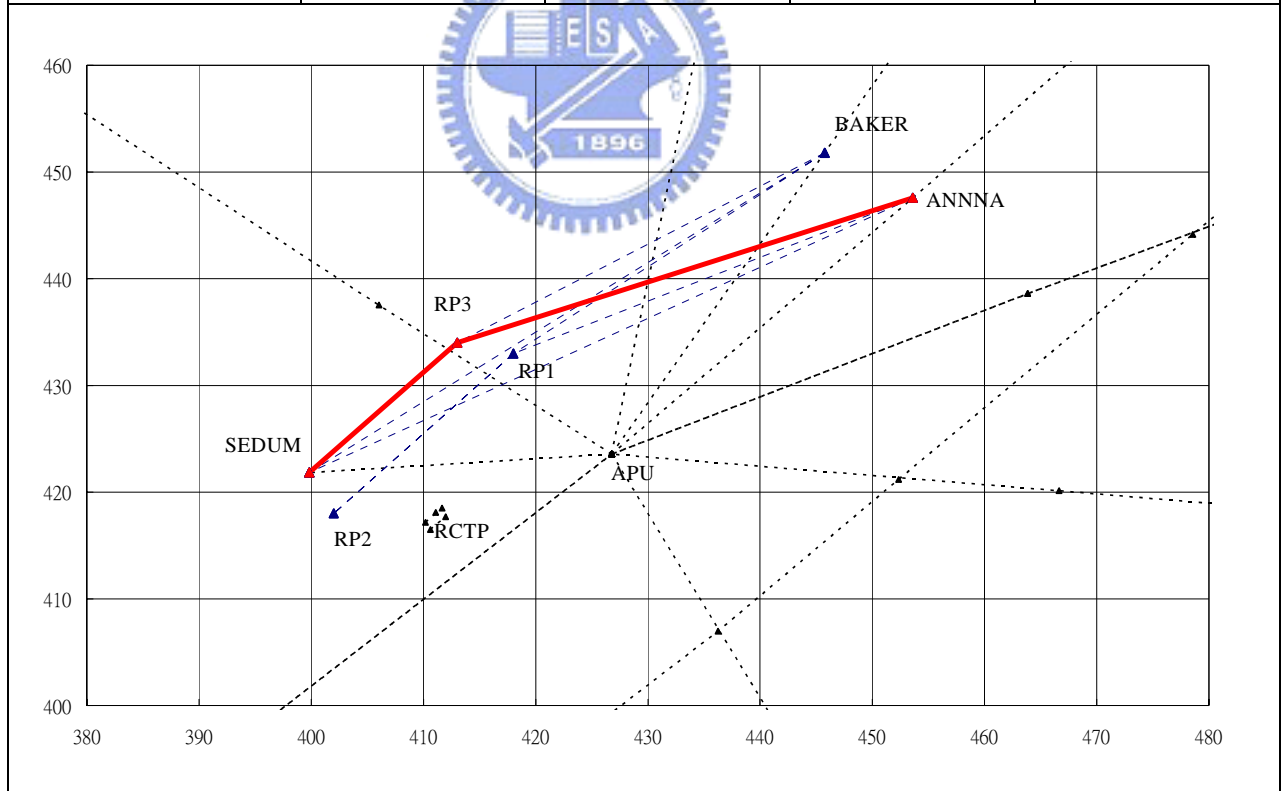
附表 4 R4-速度程序及高度指示一覽表

速度程序 (Speed Profile)	ANNNA	RP1	SEDUM
Profile A (Normal) 通過時間: 660s (±5%)	GS: 400kt (IAS: 300kt) FL200	GS: 290kt (IAS: 240kt) 10000ft	GS: 250kt (IAS: 230kt) 5000±1000ft
Profile B (Low Speed) 通過時間: 723s (±5%)	GS: 340kt (IAS: 240kt) FL200	GS: 290kt (IAS: 240kt) 10000ft	GS: 250kt (IAS: 230kt) 5000±1000ft
Profile C (High Speed) 通過時間: 590s (±5%)	GS: 430kt (IAS: 330kt) FL200	GS: 360kt (IAS: 310kt) 10000ft	GS: 280kt (IAS: 255kt) 5000±1000ft



附表 5 R5-速度程序及高度指示一覽表

速度程序 (Speed Profile)	ANNNA	RP3 前 6 哩	RP3	SEDUM
Profile A (Normal) 通過時間: 687s (±5%)	GS: 400kt (IAS: 300kt) FL200	GS: 350kt (IAS: 295kt) FL110	GS: 290kt (IAS: 240kt) 10000ft	GS: 250kt (IAS: 230kt) 5000±1000ft
Profile B (Low Speed) 通過時間: 750s (±5%)	GS: 340kt (IAS: 240kt) FL200	無	GS: 290kt (IAS: 240kt) 10000ft	GS: 250kt (IAS: 230kt) 5000±1000ft
Profile C (High Speed) 通過時間: 612s	GS: 430kt (IAS: 330kt) FL200	無	GS: 360kt (IAS: 310kt) 10000ft	GS: 280kt (IAS: 255kt) 5000±1000ft



附表 6 R6-速度程序及高度指示一覽表

速度程序 (Speed Profile)	ANNNA	RP1 前 6 哩	RP1	RP2
Profile A (Normal) 通過時間: 650s (±5%)	GS: 400kt (IAS: 300kt) FL200	GS: 350kt (IAS: 295kt) FL110	GS: 290kt (IAS: 240kt) 10000ft	GS: 250kt (IAS: 230kt) 5000±1000ft
Profile B (Low Speed) 通過時間: 712s (±5%)	GS: 340kt (IAS: 240kt) FL200	無	GS: 290kt (IAS: 240kt) 10000ft	GS: 250kt (IAS: 230kt) 5000±1000ft
Profile C (High Speed) 通過時間: 580s (±5%)	GS: 430kt (IAS: 330kt) FL200	無	GS: 360kt (IAS: 310kt) 10000ft	GS: 280kt (IAS: 255kt) 5000±1000ft

